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Semiconductor devices - Part 5-5: Optoelectronic devices - Photocouplers

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 11/20

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EUROPÄISCHE NORM

September 2020

ICS 31.080.01; 31.260

Supersedes EN 60747-5-5:2011 and all of its
amendments and corrigenda (if any)

English Version

**Semiconductor devices - Part 5-5: Optoelectronic devices -
Photocouplers
(IEC 60747-5-5:2020)**Dispositifs à semiconducteurs - Partie 5-5 : Dispositifs
optoélectroniques - Photocoupleurs
(IEC 60747-5-5:2020)Halbleiterbauelemente - Teil 5-5: Optoelektronische
Bauelemente - Optokoppler
(IEC 60747-5-5:2020)

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Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 60747-5-5:2020 (E)**European foreword**

The text of document 47E/706/FDIS, future edition 2 of IEC 60747-5-5, prepared by SC 47E "Discrete semiconductor devices" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60747-5-5:2020.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2021-05-24 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2023-08-24 document have to be withdrawn

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The text of the International Standard IEC 60747-5-5:2020 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60065	NOTE	Harmonized as EN 60065
IEC 60270:2000	NOTE	Harmonized as EN 60270:2001 (not modified)
IEC 60747-5-2	NOTE	Harmonized as EN 60747-5-2
IEC 60747-5-3	NOTE	Harmonized as EN 60747-5-3

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	2013	Environmental testing - Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-1	-	Environmental testing - Part 2-1: Tests - Test A: Cold	EN 60068-2-1	-
IEC 60068-2-2	-	Environmental testing - Part 2-2: Tests - Test B: Dry heat	EN 60068-2-2	-
IEC 60068-2-6	-	Environmental testing - Part 2-6: Tests - Test Fc: Vibration (sinusoidal)	EN 60068-2-6	-
IEC 60068-2-14	-	Environmental testing - Part 2-14: Tests - Test N: Change of temperature	EN 60068-2-14	-
IEC 60068-2-17	-	Basic environmental testing procedures - Part 2-17: Tests - Test Q: Sealing	EN 60068-2-17	-
IEC 60068-2-20	-	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	-
IEC 60068-2-27	-	Environmental testing - Part 2-27: Tests - Test Ea and guidance: Shock	EN 60068-2-27	-
IEC 60068-2-30	-	Environmental testing - Part 2-30: Tests - Test Db: Damp heat, cyclic (12 h + 12 h cycle)	EN 60068-2-30	-
IEC 60068-2-58	-	Environmental testing - Part 2-58: Tests - Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)	EN 60068-2-58	-
IEC 60068-2-78	-	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	-
IEC 60112	-	Method for the determination of the proof and the comparative tracking indices of solid insulating materials	EN 60112	-

EN IEC 60747-5-5:2020 (E)

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60216-1	-	Electrical insulating materials - Thermal endurance properties - Part 1: Ageing procedures and evaluation of test results	EN 60216-1	-
IEC 60216-2	-	Electrical insulating materials - Thermal endurance properties - Part 2: Determination of thermal endurance properties of electrical insulating materials - Choice of test criteria	EN 60216-2	-
IEC 60664-1	2007	Insulation coordination for equipment within low-voltage systems - Part 1: Principles, requirements and tests	EN 60664-1	2007
IEC 60672-2	-	Ceramic and glass insulating materials - Part 2: Methods of test	EN 60672-2	-
IEC 60695-11-5	-	Fire hazard testing - Part 11-5: Test flames - Needle-flame test method - Apparatus, confirmatory test arrangement and guidance	EN 60695-11-5	-
IEC 61000-4-5	-	Electromagnetic compatibility (EMC) - Part 4-5: Testing and measurement techniques - Surge immunity test	EN 61000-4-5	-
IEC 62368-1	2018	Audio/video, information and communication technology equipment - Part 1: Safety requirements	EN IEC 62368-1	2020



IEC 60747-5-5

Edition 2.0 2020-07

INTERNATIONAL STANDARD

**Semiconductor devices –
Part 5-5: Optoelectronic devices – Photocouplers**





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67 000 electrotechnical terminology entries in English and French extracted from the Terms and Definitions clause of IEC publications issued since 2002. Some entries have been collected from earlier publications of IEC TC 37, 77, 86 and CISPR.



IEC 60747-5-5

Edition 2.0 2020-07

INTERNATIONAL STANDARD

**Semiconductor devices –
Part 5-5: Optoelectronic devices – Photocouplers**

INTERNATIONAL
ELECTROTECHNICAL
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES –**Part 5-5: Optoelectronic devices –
Photocouplers**

FOREWORD

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International Standard IEC 60747-5-5 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2007 and Amendment 1:2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) optional data sheet basic insulation rating in accordance with IEC 60664-1:2007, 6.1.3.5;
- b) editorial corrections on the use of V_{IORM} ;
- c) editorial corrections on Figure 2: Time intervals for method b);
- d) addition of an alternative surge pulse V_{IOSM} test method.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
47E/706/FDIS	47E/714/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60747 series, published under the general title *Semiconductor devices*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

SEMICONDUCTOR DEVICES –

Part 5-5: Optoelectronic devices – Photocouplers

1 Scope

This part of IEC 60747 specifies the terminology, essential ratings, characteristics, safety tests, as well as the measuring methods for photocouplers.

NOTE The term "optocoupler" can also be used instead of "photocoupler".

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1:2013, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-1, *Environmental testing – Part 2-1: Tests – Test A: Cold*

IEC 60068-2-2, *Environmental testing – Part 2-2: Tests – Test B: Dry heat*

IEC 60068-2-6, *Environmental testing – Part 2-6: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-14, *Environmental testing – Part 2-14: Tests – Test N: Change of temperature*

IEC 60068-2-17, *Basic environmental testing procedures – Part 2-17: Tests – Test Q: Sealing*

IEC 60068-2-20, *Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads*

IEC 60068-2-27, *Environmental testing – Part 2-27: Tests – Test Ea and guidance: Shock*

IEC 60068-2-30, *Environmental testing – Part 2-30: Tests – Test Db: Damp heat, cyclic (12 h + 12 h cycle)*

IEC 60068-2-58, *Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-78, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state*

IEC 60112, *Method for the determination of the proof and the comparative tracking indices of solid insulating materials*

IEC 60216-1, *Electrical insulating materials – Thermal endurance properties – Part 1: Ageing procedures and evaluation of test results*

IEC 60216-2, *Electrical insulating materials – Thermal endurance properties – Part 2: Determination of thermal endurance properties of electrical insulating materials – Choice of test criteria*

IEC 60664-1:2007, *Insulation coordination for equipment within low-voltage systems – Part 1: Principles, requirements and tests*

IEC 60672-2, *Ceramic and glass insulating materials – Part 2: Methods of test*

IEC 60695-11-5, *Fire hazard testing – Part 11-5: Test flames – Needle-flame test method – Apparatus, confirmatory test arrangement and guidance*

IEC 61000-4-5, *Electromagnetic compatibility (EMC) – Part 4-5: Testing and measurement techniques – Surge immunity test*

IEC 62368-1:2018, *Audio/video, information and communication technology equipment – Part 1: Safety requirements*

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